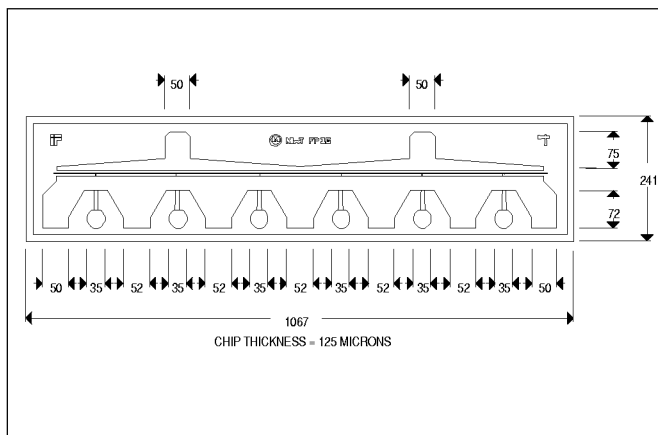


MwT-16

26 GHz High Power GaAs FET

- 0.5 WATT POWER OUTPUT AT 12 GHz
- +39 dBm THIRD ORDER INTERCEPT
- HIGH ASSOCIATED GAIN
- 0.3 MICRON REFRACTORY METAL/GOLD GATE
- 900 MICRON GATE WIDTH
- DIAMOND-LIKE CARBON PASSIVATION



DESCRIPTION

The MwT-16 is a GaAs MESFET device whose nominal quarter-micron gate length and 900 micron gate width make it ideally suited to applications requiring high-power output in the 2 GHz to 18 GHz frequency range. The straight gate geometry of the MwT-16 makes it equally effective for either wideband (e.g. 6 to 18 GHz) or narrow-band applications. The chip is produced using MwT's reliable metal system and all devices are screened to insure reliability. All chips are passivated using MwT's patented "Diamond-Like Carbon" process for increased durability. Designers can use MwT's unique BIN selection feature to choose devices from narrow Idss ranges, insuring consistent circuit operation.

RF SPECIFICATIONS AT Ta = 25°C

| | | | | MwT-16 HP | |
|--------|---|--------|-------|-----------|---------|
| SYMBOL | PARAMETERS AND CONDITIONS | FREQ | UNITS | MIN | TYP |
| P1dB | Output Power at 1dB Compression VDS=6.0 V IDS=150 mA | 12 GHz | dBm | 26.0 | 27.0 |
| SSG | Small Signal Gain VDS=6.0 V IDS=150 mA | 12 GHz | dB | 7.5 | 8.5 |
| PAE | Power Added Efficiency VDS=6.0 V IDS=150 mA | 12GHz | % | 25 | 35 |
| IDSS | Recommended IDSS Range for Optimum P1dB | | mA | | 240-330 |

AVAILABLE IN CHIP FORM ONLY

DC SPECIFICATIONS AT Ta = 25 °C

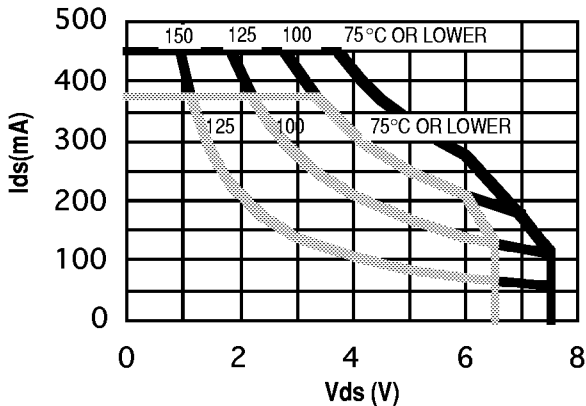
| SYMBOL | PARAMETERS AND CONDITIONS | UNITS | MIN | TYP | MAX |
|--------------|---|-------|------|-------|------|
| Idss | Saturated Drain Current Vds=4.0 V VGS=0.0 V | mA | 90 | | 360 |
| Gm | Transconductance Vds=2.0 V VGS=0.0 V | mS | 108 | 130 | |
| Vp | Pinch-off Voltage Vds=3.0 V IDS=6.0 mA | V | | -2.0 | -5.0 |
| BVGSO | Gate-to-Source Breakdown Voltage Igs=-0.6 mA | V | -6.0 | -12.0 | |
| BVGDO | Gate-to-Drain Breakdown Voltage Igd=-0.6 mA | V | -8.0 | -12.0 | |
| Rth | Thermal Resistance MwT-16 Chip | °C/W | | 55 | |

MAXIMUM RATINGS AT Ta = 25 °C

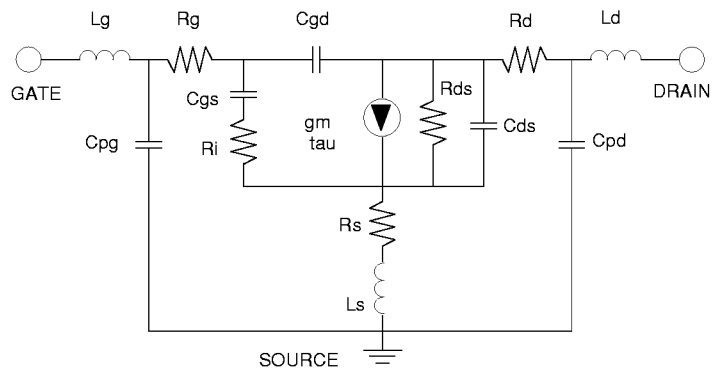
| SYMBOL | PARAMETER | UNITS | CONT MAX ¹ | ABSOLUTE MAX ² |
|--------|-------------------------|-------|---------------------------|---------------------------|
| VDS | Drain to Source Voltage | V | See Safe Operating Limits | |
| Tch | Channel Temperature | °C | +150 | +175 |
| Tst | Storage Temperature | °C | -65 to +150 | +175 |
| Pin | RF Input Power | mW | 280 | 430 |

NOTES: 1. Exceeding any one of these limits in continuous operation may reduce the mean-time-to-failure below the design goals.
2. Exceeding any one of these limits may cause permanent damage.

SAFE OPERATING LIMITS vs. Case Temperature



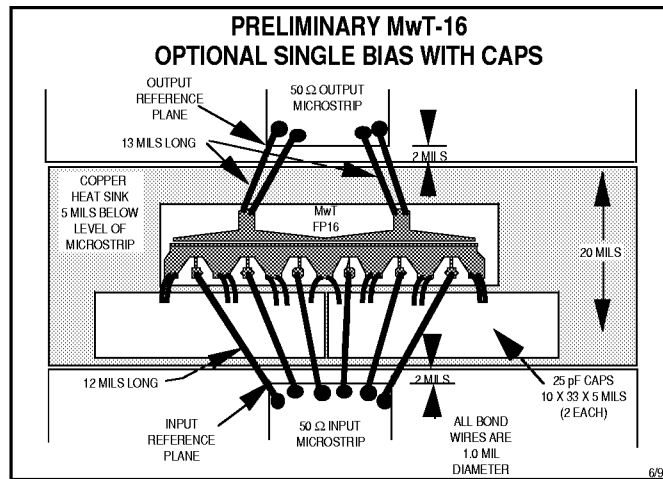
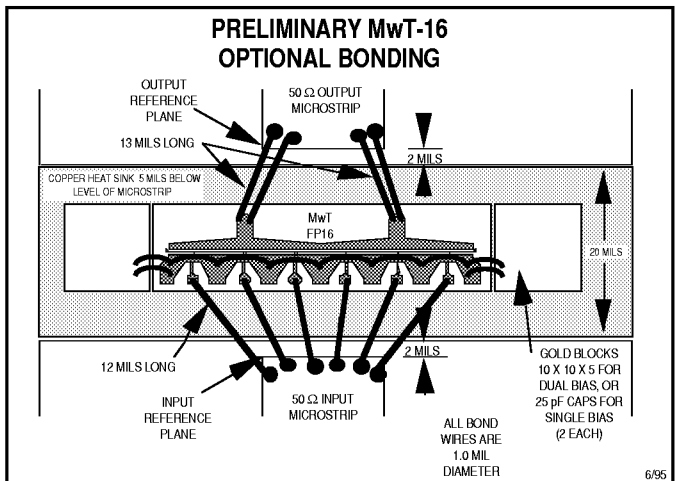
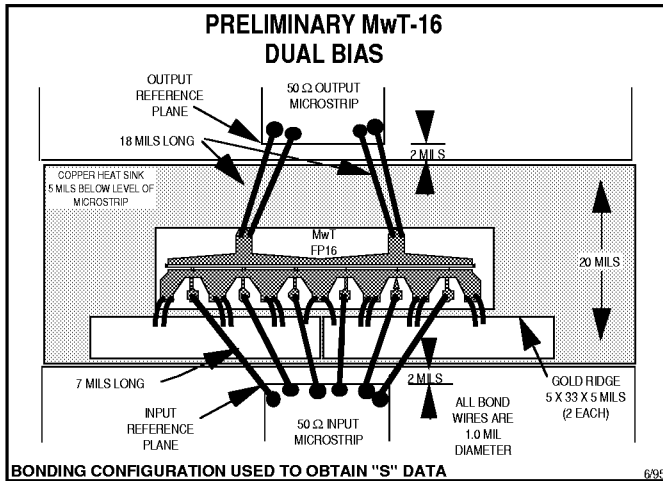
DEVICE EQUIVALENT CIRCUIT MODEL



| PARAMETER | VALUE | PARAMETER | VALUE |
|---------------------------|--------------|--------------------------|-------------|
| Gate Bond Wire Inductance | Lg 0.05 nH | Source Resistance | Rs 0.60 Ω |
| Gate Pad Capacitance | Cpg 0.50 pF | Source Inductance | Ls 0.04 nH |
| Gate Resistance | Rg 0.30 Ω | Drain-Source Resistance | Rds 150.0 Ω |
| Gate-Source Capacitance | Cgs 0.85 pF | Drain-Source Capacitance | Cds 0.01 pF |
| Channel Resistance | Ri 1.0 Ω | Drain Resistance | Rd 1.0 Ω |
| Gate-Drain Capacitance | Cgd 0.06 pF | Drain Pad Capacitance | Cpd 0.20 pF |
| Transconductance | gm 140.0 mS | Drain Inductance | Ld 0.09 nH |
| Transit time | tau 1.9 psec | | |

RECOMMENDED ASSEMBLY CONFIGURATION

Shown below is the assembly and bonding configuration used for S-Parameter measurements of the MwT-16 chip. This configuration is recommended for optimum performance. For single-bias applications the gold blocks may be replaced by capacitors. An additional interconnecting bond would then be required. Contact MwT for additional applications information.



BIN SELECTION

Every MwT-16 wafer has been probed for I_{dss} and the data stored on computer disk. Customers may select from I_{dss} values in any of 18 current bins, as shown below, to insure consistent performance in their circuit. The shaded bins are typically available in smaller quantity and caution is advised before designing these bins into high production applications. MwT's "Smart Wafer Picker" reads the stored I_{dss} Data from the disk and devices from customer selected bins are quickly and automatically picked from the wafer and loaded into shipping containers.

| BIN# | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | 13 | 14 | 15 | 16 | 17 | 18 |
|-----------|--------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|---------|
| IDSS (mA) | 90-105 | 105-120 | 120-135 | 135-150 | 150-165 | 165-180 | 180-195 | 195-210 | 210-225 | 225-240 | 240-255 | 255-270 | 270-285 | 285-300 | 300-315 | 315-330 | 330-345 | 345-360 |

BIN ACCURACY

Due to the effects of temperature, dc loading and probe tip varnishing, the I_{dss} from the "on wafer" probing of any MwT device may differ after it has been attached to a proper heat sink and tested in an RF or DC circuit.

Because of the aforementioned effects, the I_{dss} distribution may deviate as much as +/- 1 bin within the range identified on the label of each die shipping container, and +/- 2 bins within the selected range.

DEVICE HANDLING PROCEDURE

- 1) Open package in clean room environment only.
- 2) GaAs FETs are sensitive to electrostatic discharge. Precautions should be taken in handling, die attachment, and bonding to assure that Maximum Ratings are not exceeded as a result of electrical discharge.
- 3) Chips have been cleaned and are ready for die attachment. DO NOT attempt to re-clean.
- 4) Assembly should be performed with parts no hotter than 300° C. All circuit components (such as resistors and capacitors) should be assembled completely before the FET is die attached. Assembly should be performed as quickly as possible. In general, no chip should be left at 300°C for over 2 minutes.
- 5) Die attach with clean AuSn alloy under forming gas at 280 to 300° C. Scrub chip down with tweezers. Thermal resistance is critically dependent on this operation.
- 6) Thermasonic wedge bonding is recommended. A .0015 in. bond flat wedge at 125 to 150° C should be used with a heater stage temperature of 200 to 225° C. Apply 15 to 20 grams of bond force to .001 in. diameter gold wire with an elongation of 2 to 5%.
- 7) Store in a clean, dry, inert environment such as nitrogen at room temperature.
- 8) CAUTION: Handling of chips other than as specified above may cause permanent damage.

TYPICAL COMMON SOURCE SCATTERING PARAMETERS

MwT-16 CHIP: VDS = 6.0 V, IDS = 0.6 IDSS = 150 mA

| FREQUENCY (MHz) | S11 | | S21 | | S12 | | S22 | |
|--------------------|-----|--------|------|-------|------|------|-----|--------|
| | MAG | ANG | MAG | ANG | MAG | ANG | MAG | ANG |
| 1000 | .98 | -55.3 | 8.48 | 147.8 | .029 | 60.6 | .47 | -27.6 |
| 2000 | .94 | -92.0 | 6.51 | 123.9 | .045 | 43.6 | .40 | -43.2 |
| 3000 | .91 | -116.0 | 5.02 | 107.4 | .053 | 30.6 | .36 | -55.0 |
| 4000 | .89 | -130.7 | 4.03 | 96.0 | .054 | 23.9 | .35 | -64.1 |
| 5000 | .89 | -141.5 | 3.35 | 86.5 | .052 | 23.1 | .34 | -71.6 |
| 6000 | .90 | -149.8 | 2.86 | 77.7 | .054 | 19.2 | .35 | -80.3 |
| 7000 | .89 | -156.1 | 2.45 | 70.0 | .051 | 15.5 | .37 | -88.4 |
| 8000 | .88 | -160.8 | 2.14 | 63.3 | .048 | 13.5 | .40 | -96.0 |
| 9000 | .89 | -164.2 | 1.89 | 57.7 | .046 | 10.7 | .42 | -102.6 |
| 10000 | .89 | -167.4 | 1.71 | 51.9 | .040 | 12.2 | .46 | -108.9 |
| 12000 | .92 | -172.9 | 1.41 | 41.4 | .025 | 26.7 | .51 | -119.6 |
| 14000 | .92 | -177.0 | 1.17 | 30.9 | .034 | 40.6 | .58 | -126.6 |
| 16000 | .90 | -179.1 | .95 | 22.4 | .030 | 44.2 | .65 | -133.0 |
| 18000 | .91 | 179.1 | .82 | 15.8 | .025 | 52.0 | .70 | -137.5 |
| 20000 | .92 | 177.0 | .70 | 9.3 | .026 | 82.2 | .76 | -141.1 |
| 22000 | .91 | 176.0 | .61 | 3.4 | .033 | 77.5 | .79 | -142.4 |
| 24000 | .90 | 174.8 | .54 | -3.0 | .040 | 68.6 | .79 | -144.2 |
| 26000 | .93 | 174.0 | .50 | -8.3 | .023 | 77.5 | .82 | -145.1 |